EXAMINER				50478-0700 Applicant(s) Wataru Ikeda et al. Filing Date September 18, 2006 U. S. PATENT DOCUMENTS		Application Number 10/573,137 Group Art Unit 2627 FILING DATE		
INITIAL	KEF	DOCUMEN I NUMBER	DATE	NAME	CLASS	SUBCLASS	IF APPR	OPRIATE
EXAMINER	REF	DOCUMENT NUMBER	T	NT APPLICATION PUBL			FILIN	G DATE
INITIAL	KEF	2004/0175154	9.9.2004	Yoon et al.	CLASS	SUBCLASS	IF APPR	OPRIATE
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		отні	ER DOCUME	NTS (Including Author, Title, Date	, Pertinent Pages, Etc.)			
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